

## LECTURE 160 – BIPOLAR TECHNOLOGY

(READING: Text-Sec. 2.4, 2.5)

### INTRODUCTION

#### **Objective**

The objective of this presentation is:

- 1.) Illustrate the fabrication sequence for a typical bipolar junction transistor
- 2.) Show the physical aspects of the BJT

#### **Outline**

- *npn* BJT technology
- Compatible *pnp* BJTs
- Modifications to the standard *npn* BJT technology
- Advanced BJT technology
- Summary

## ***npn* BIPOLAR JUNCTION TRANSISTOR TECHNOLOGY**

### **Major Processing Steps for a Junction Isolated BJT Technology**

Start with a *p* substrate.

1. Implantation of the buried  $n^+$  layer
2. Growth of the epitaxial layer
3.  $p^+$  isolation diffusion
4. Base *p*-type diffusion
5. Emitter  $n^+$  diffusion
6.  $p^+$  ohmic contact
7. Contact etching
8. Metal deposition and etching
9. Passivation and bond pad opening

### Implantation of the Buried Layer (Mask Step 1)

Objective of the buried layer is to reduce the collector resistance.

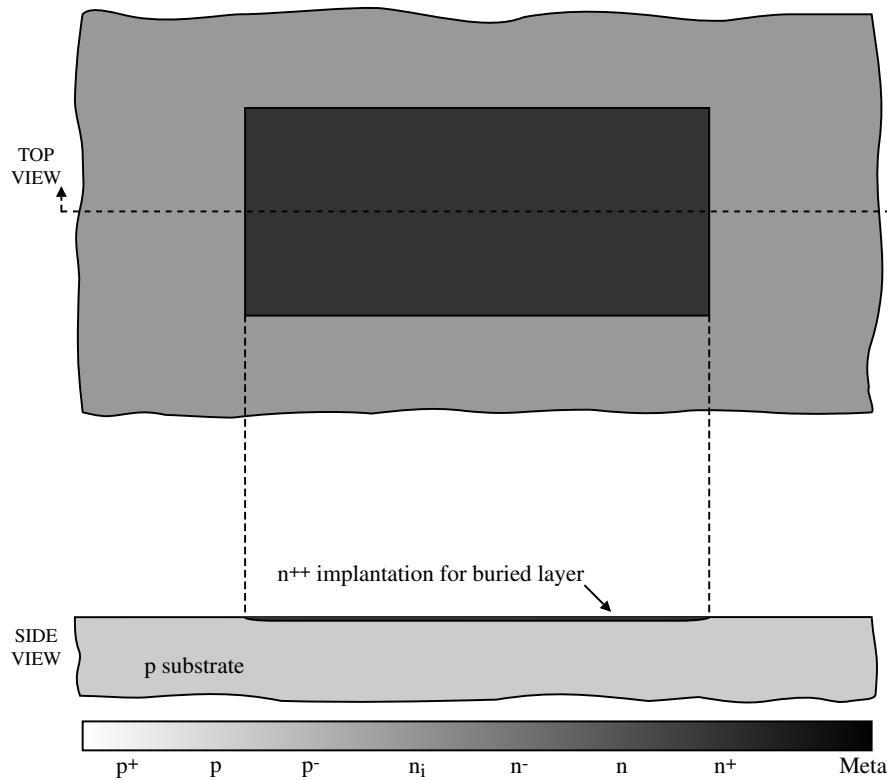


Fig.160-01

### Epitaxial Layer (No Mask Required)

The objective is to provide the proper *n*-type doping in which to build the *npn* BJT.

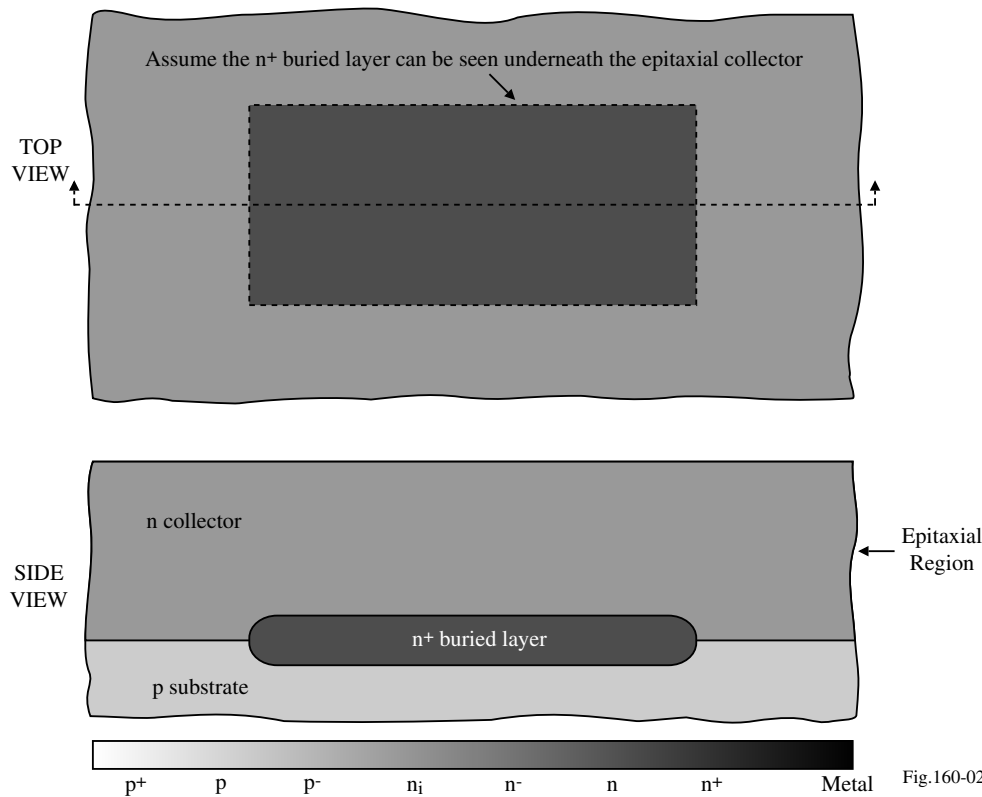


Fig.160-02

### **$p^+$ isolation diffusion (Mask Step 2)**

The objective of this step is to surround (isolate) the  $npn$  BJT by a  $p^+$  diffusion. These regions also permit contact to the substrate from the surface.

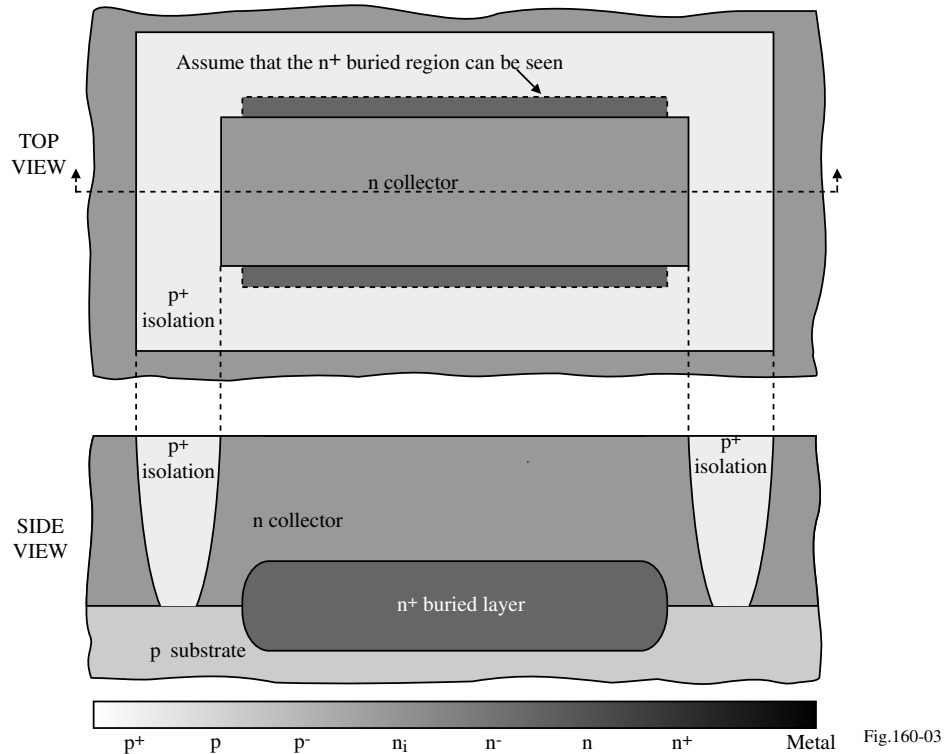


Fig.160-03

### **Base $p$ -type diffusion (Mask Step 3)**

The step provides the  $p$ -type base for the  $npn$  BJT.

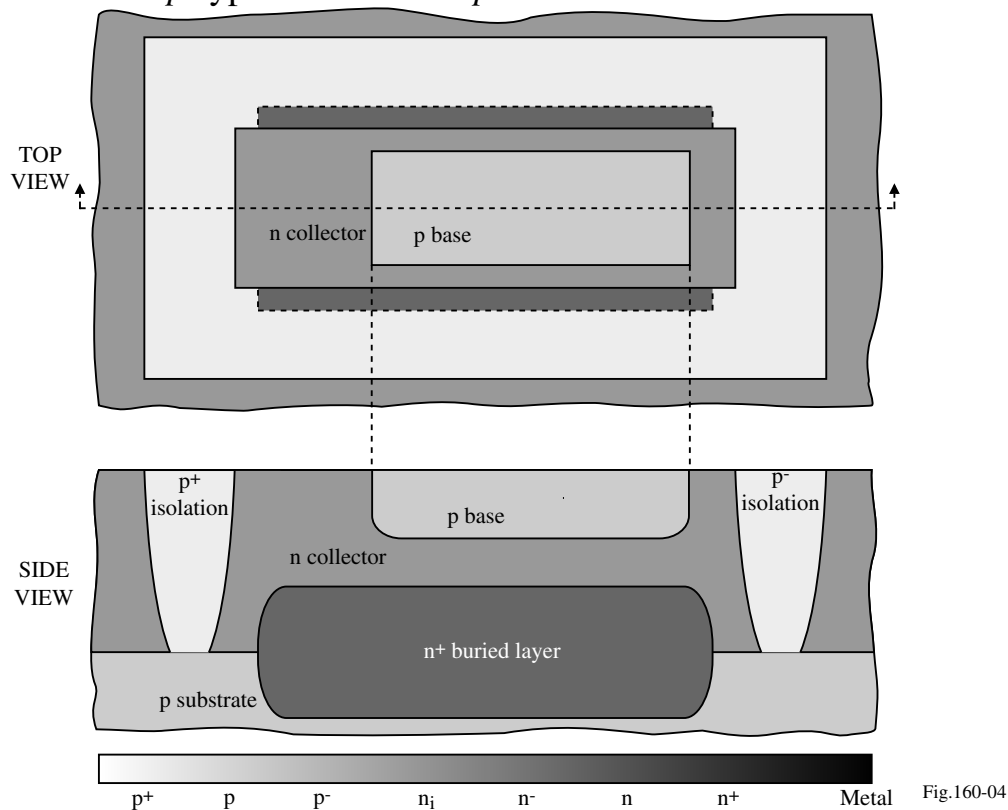


Fig.160-04

### Emitter $n^+$ diffusion (Mask Step 4)

This step implements the  $n^+$  emitter of the  $npn$  BJT and the collector ohmic contact.

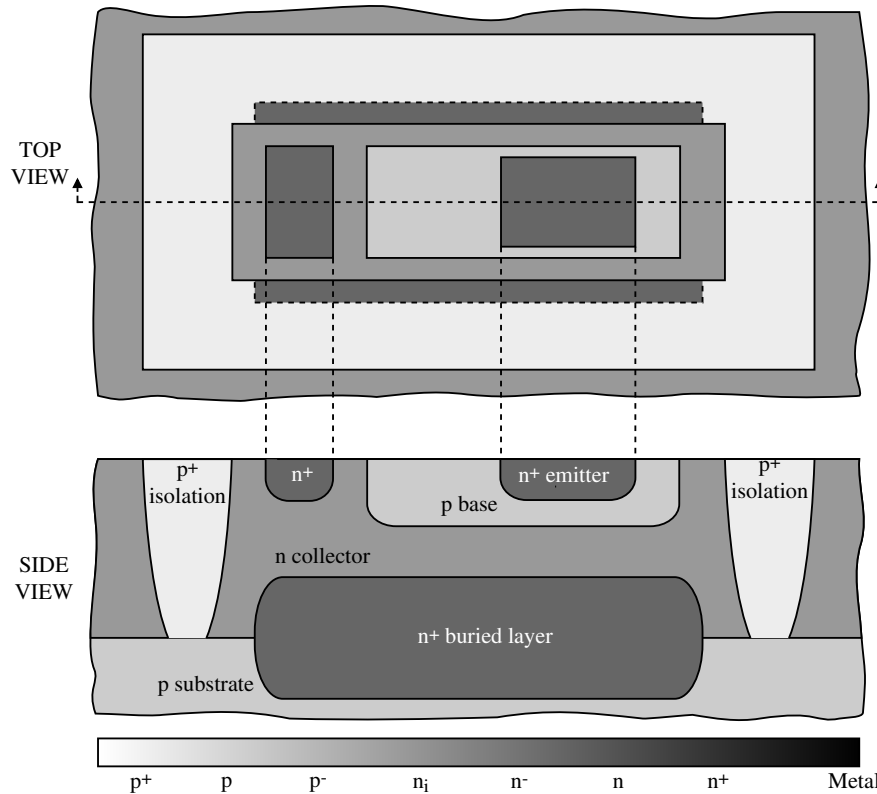


Fig.160-05

### $p^+$ ohmic contact (Mask Step 5)

This step permits ohmic contact to the base region if it is not doped sufficiently high.

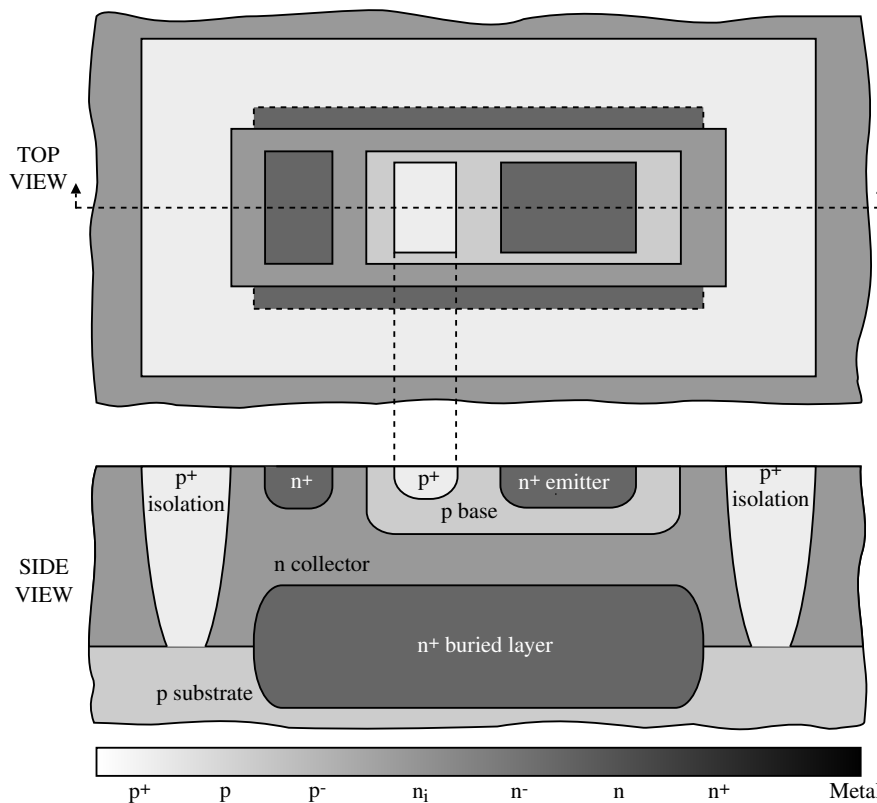


Fig.160-06

### Contact etching (Mask Step 6)

This step opens up the areas in the dielectric area which metal will contact.

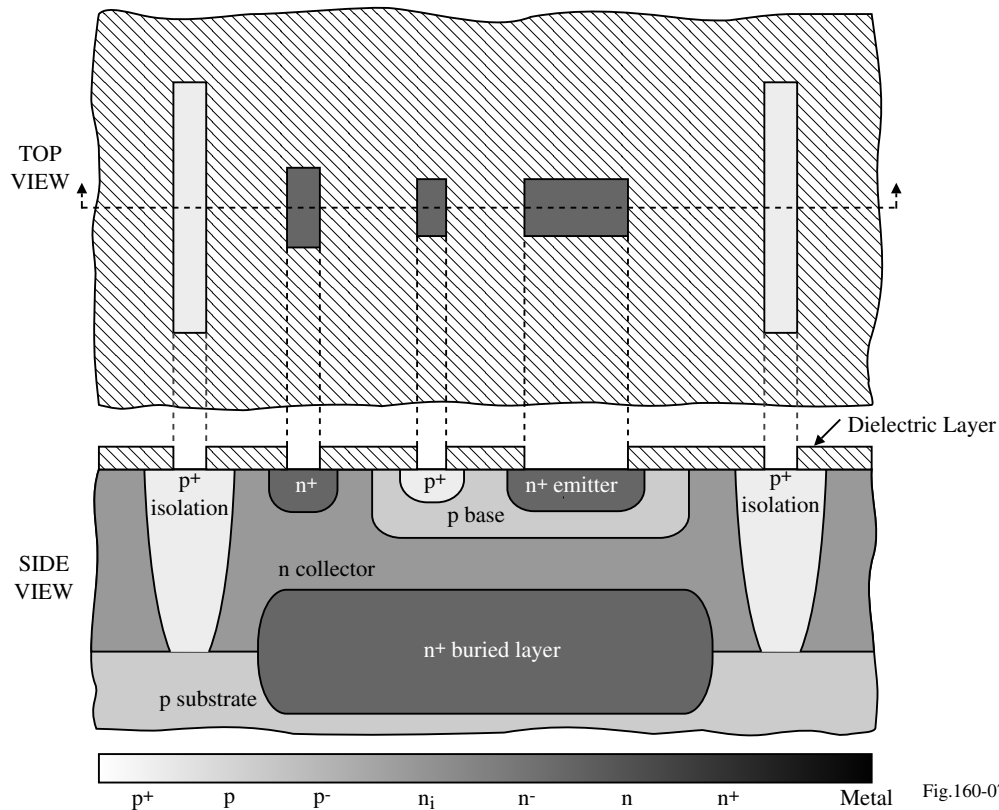


Fig.160-07

### Metal deposition and etching (Mask Step 7)

In this step, the metal is deposited over the entire wafer and removed where it is not wanted.

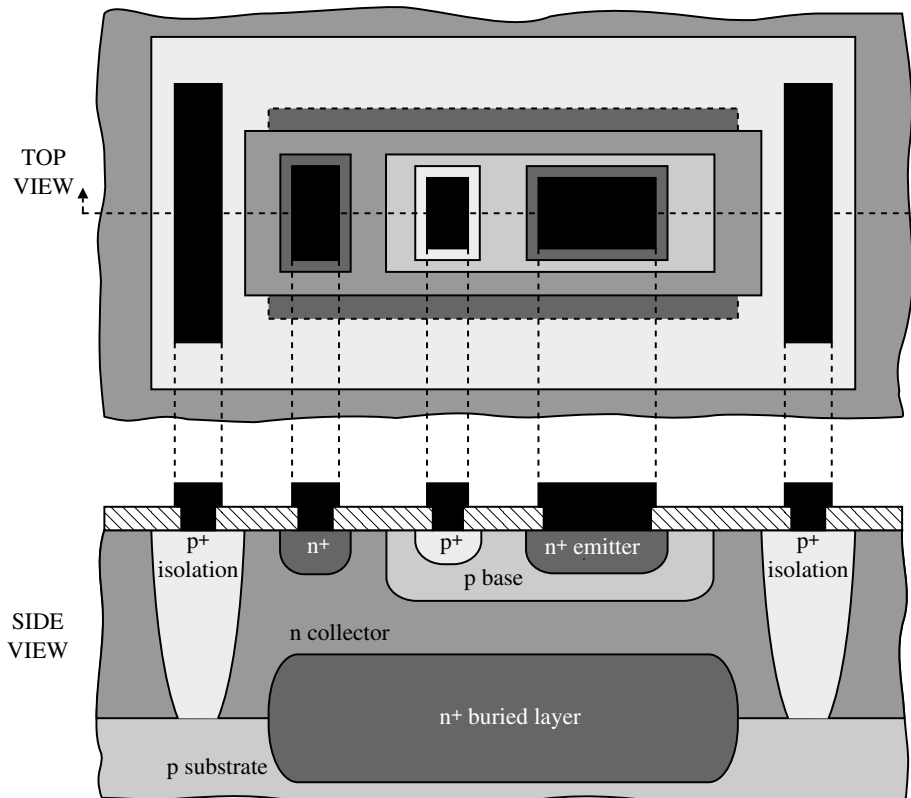


Fig.160-08

### Passivation (Mask Step 8)

Covering the entire wafer with glass and opening the area over bond pads (which requires another mask).

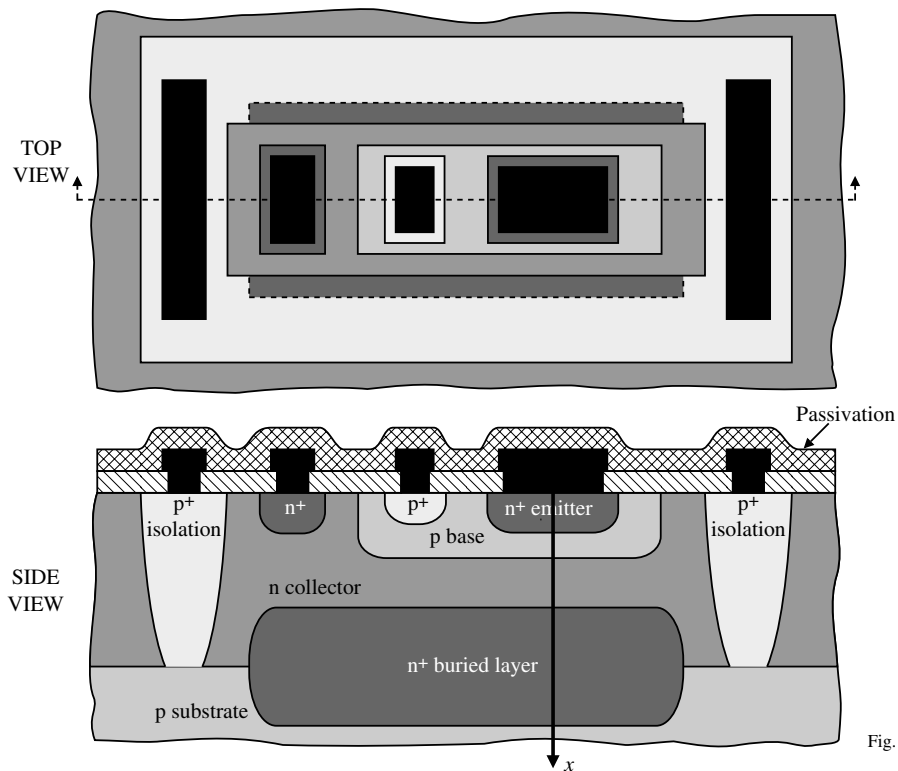


Fig.160-09

### Typical Impurity Concentration Profile for the npn BJT

Taken along the line from the surface indicated in the last slide.

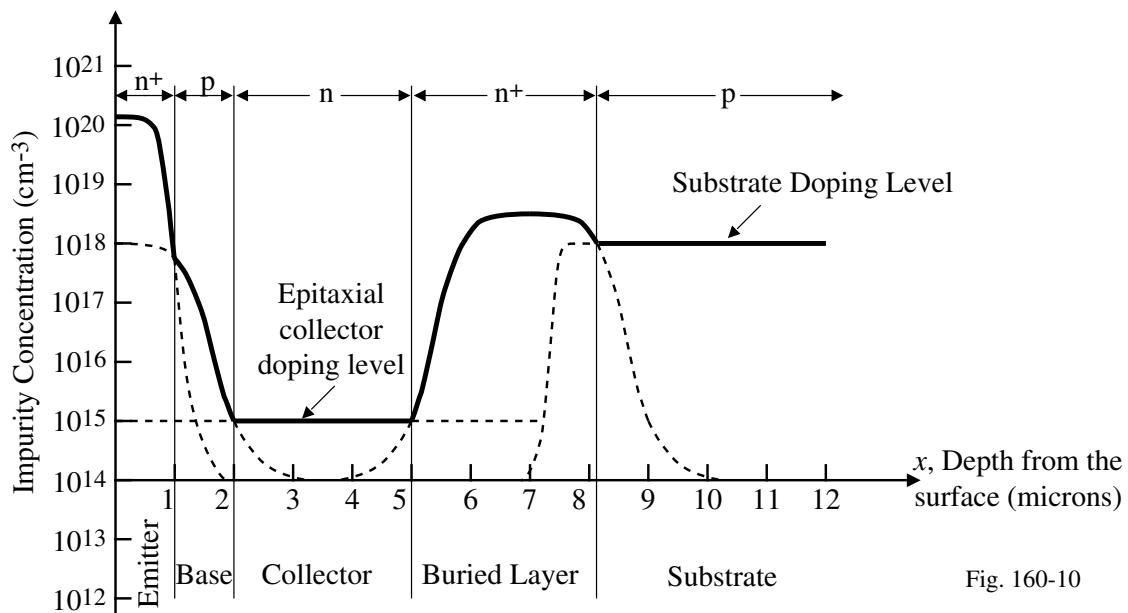


Fig. 160-10

## COMPATIBLE *pnp* BJTS

### Substrate *pnp* BJT

Collector is always connected to the substrate potential which is the most negative DC potential.

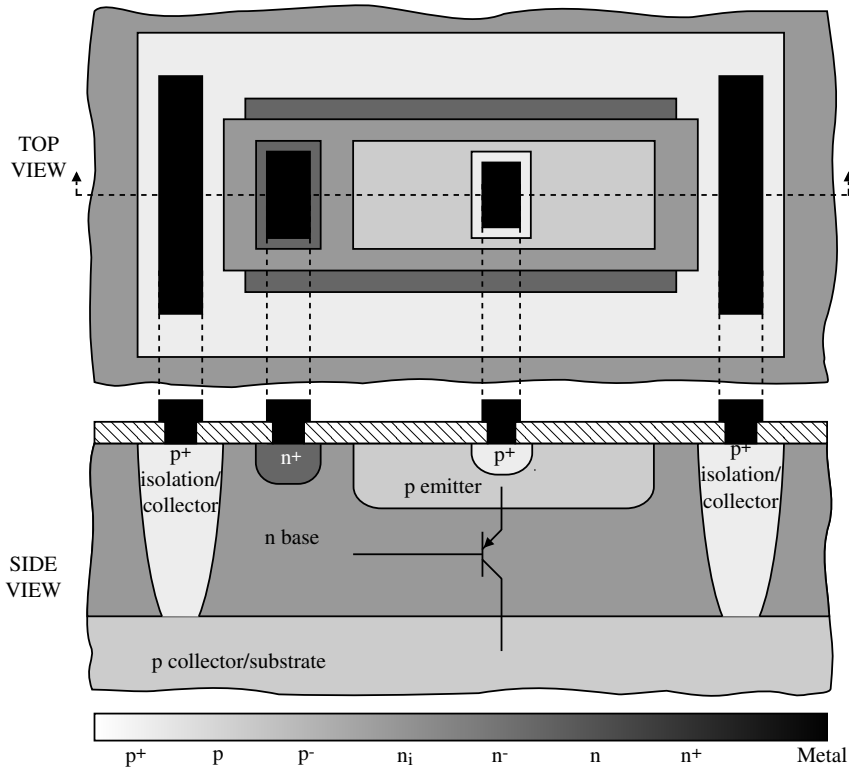


Fig.160-11

### Lateral *pnp* BJT

Collector is not constrained to a fixed dc potential.

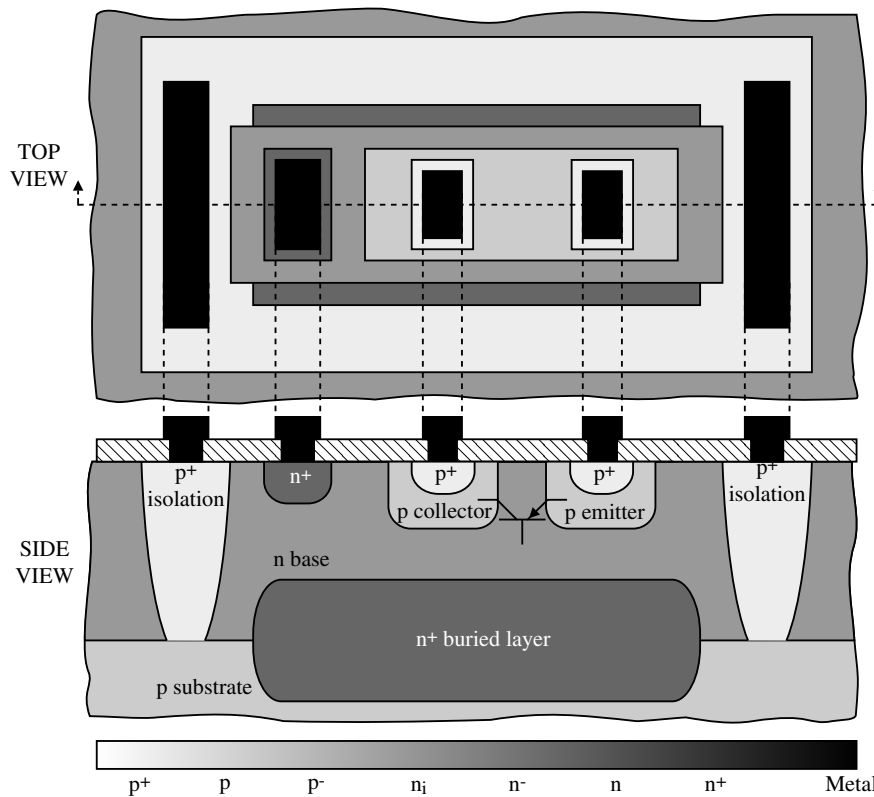


Fig.160-12

## MODIFICATIONS TO THE STANDARD *npn* TECHNOLOGY

### Types of Modifications

- 1.) Dielectric isolation - Isolation of the transistor from the substrate using an oxide layer.
- 2.) Double diffusion - A second, deeper  $n^+$  emitter diffusion is used to create JFETs.
- 3.) Ion implanted JFETs - Use of an ion implantation to create the upper gate of a p-channel JFET
- 4.) Superbeta transistors - Use of a very thin base width to achieve higher values of  $\beta_F$ .
- 5.) Double diffused *pnp* BJT - Double diffusion is used to build a vertical *pnp* transistor whose performance more closely approaches that of the *npn* BJT.

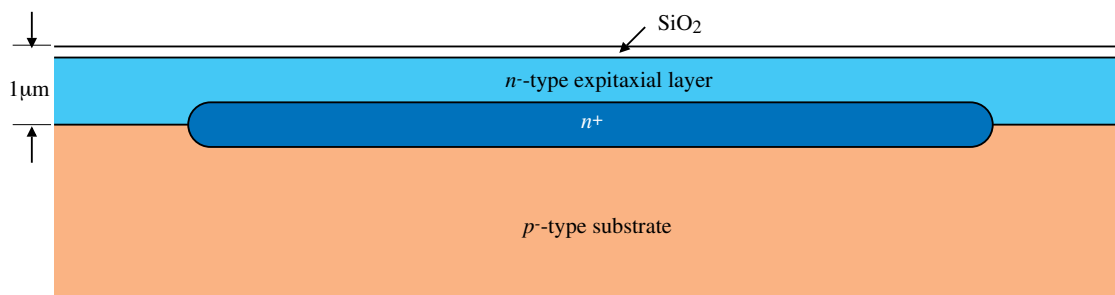
## ADVANCED BIPOLAR IC TECHNOLOGY

### Objective

Newer BJT technologies use polysilicon to form a self-aligned emitter resulting in higher frequency response capability. These technologies attempt to keep the surface of the integrated circuit as flat as possible.

### Process

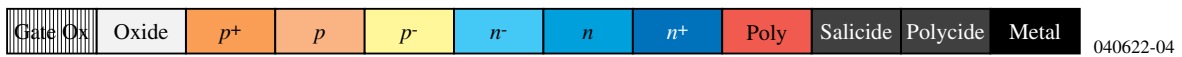
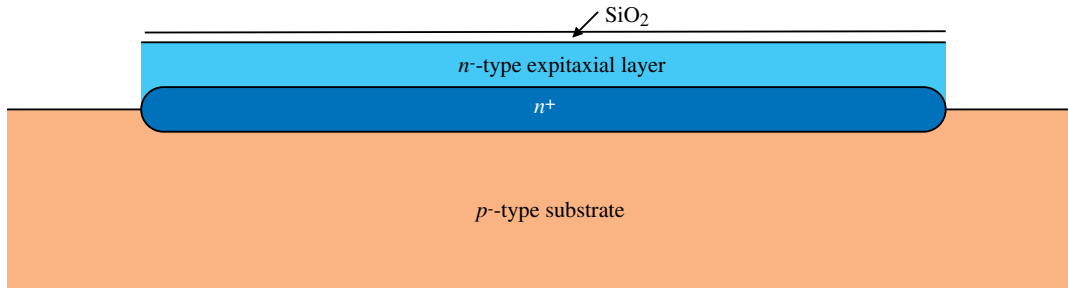
- 1.) Buried layer and epitaxial growth.



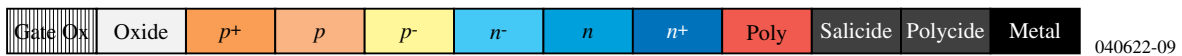
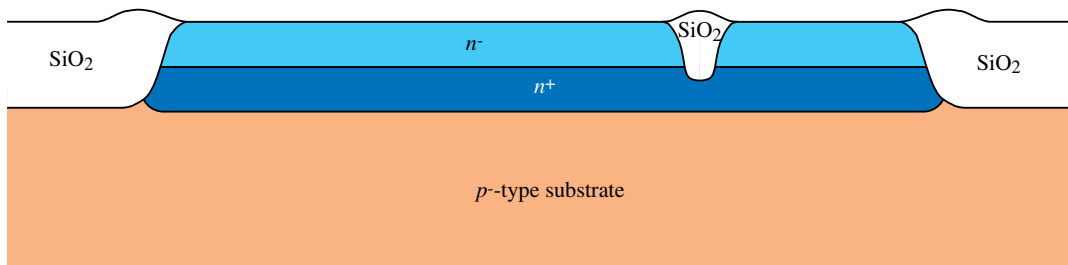


**Process – Continued**

2.) Etching of epitaxial layer.

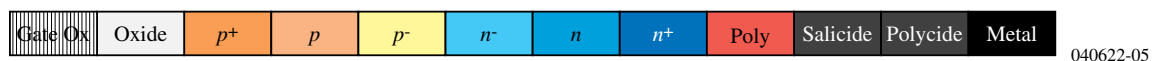
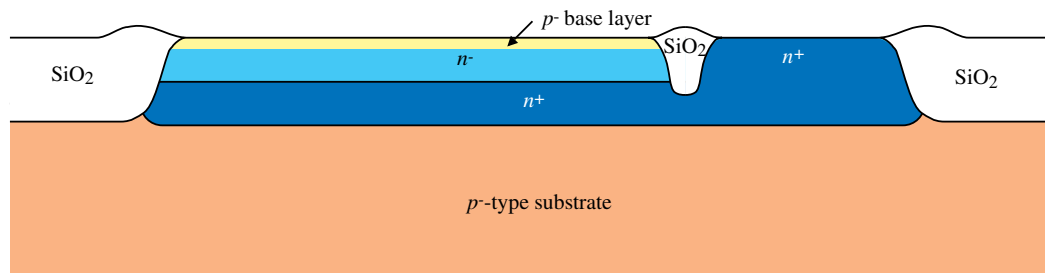


3.) Growth of thick SiO2.

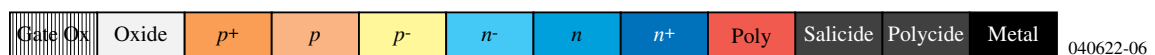
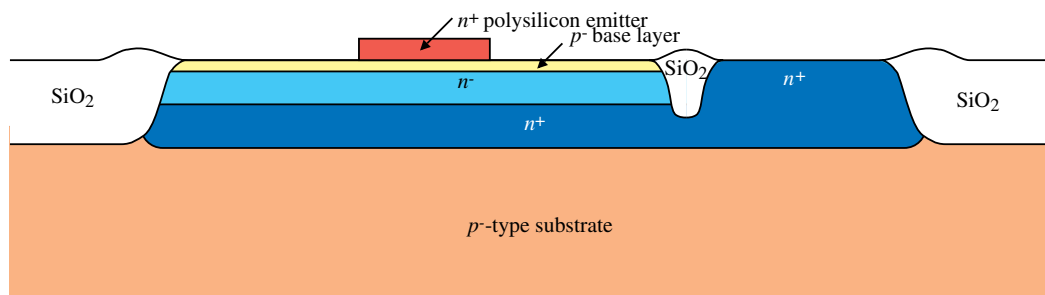


**Process – Continued**

4.) Base diffusion and collector sinker ( $n^+$  diffusion)

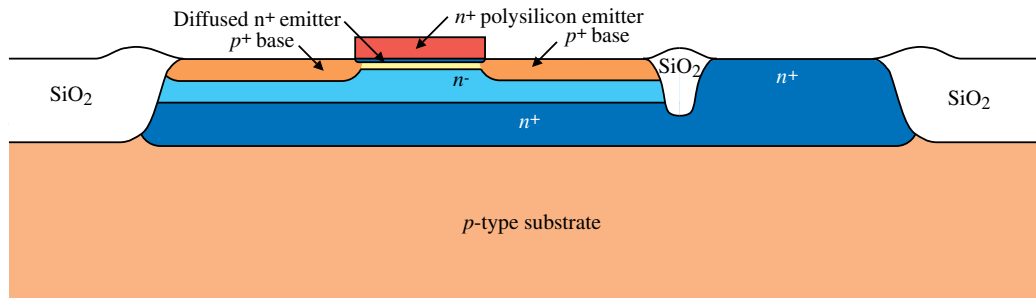


5.)  $n^+$  polysilicon emitter



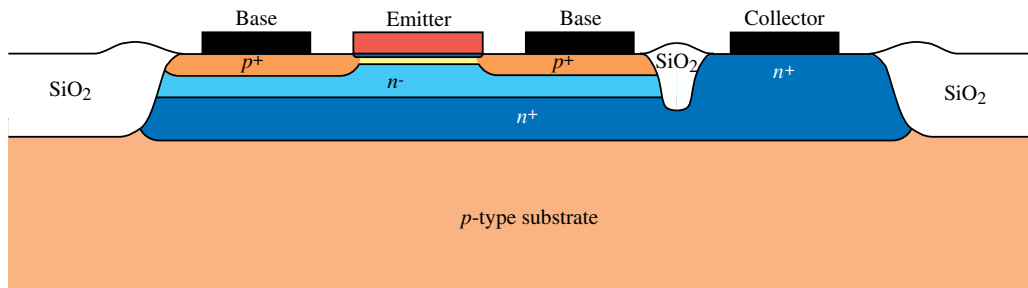
## Process – Continued

### 6.) $p^+$ base diffusion



040622-07

### 7.) Metal contacts



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## SUMMARY

The objective has been to give a physical understanding of how the  $npn$  BJT is fabricated.

- The fabrication sequence for a typical  $npn$  BJT has been illustrated
- Methods of implementing other active devices in the  $npn$  BJT technology were shown.
- Simple  $npn$  BJT technology chooses to emphasize the  $npn$  over the  $pnp$  because the  $npn$  BJT performance is always superior to the  $pnp$  BJT performance. Thus, the philosophy in design is to use the  $npn$  where ever possible and incorporate the  $pnp$  only where it has to be used.
- An advanced BJT technology has been illustrated.

We will examine the passive components that can be implemented in a typical  $npn$  BJT process later.